Power MOSFET

30 V, 20 A, Single N-Channel, SO-8 Flat Lead Package

Features

- Thermally and Electrically Enhanced Packaging Compatible with Standard SO-8
- New Package Provides Capability of Inspection and Probe After Board Mounting
- Ultra Low R_{DS(on)} (at 4.5 V_{GS}), Low Gate Resistance and Low Q_G
- Optimized for High Side Control Applications
- High Speed Switching Capability
- This is a Pb–Free Device

Applications

- Notebook Computer Vcore Applications
- Network Applications
- DC-DC Converters

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating			Symbol	Value	Unit
Drain-to-Source Voltage			V _{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain Current	Steady T _A = 25°C		I _D	12.3	Α
(Note 1)	State	T _A = 70°C		9.8	
	t ≤10 s	T _A = 25°C	I _D	20	
Power Dissipation (Note 1)	Steady State T _A = 25°C		P _D	2.3	W
	t ≤10 s	T _A = 25°C	P_{D}	6.0	
Continuous Drain Current	Steady State	T _A = 25°C	I _D	7.7	Α
(Note 2)		T _A = 70°C		6.2	
Power Dissipation (Note 2)		T _A = 25°C	P _D	0.9	W
Pulsed Drain Current $t_p = 10 \mu s$			I _{DM}	60	Α
Operating and Storage Temperature			T _J , T _{stg}	-55 to 150	°C
Source Current (Body Diode)			I _S	6.0	Α
Single Pulse Drain-to-Source Avalanche Energy (V_{DD} = 25 V, V_{GS} = 10 V, I_{PK} = 7.5 A, L = 10 mH, R_G = 25 Ω)			E _{AS}	280	mJ
Lead Temperature for Soldering Purposes (1/8 in from case for 10 s)			TL	260	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

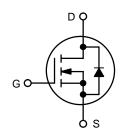
- Surface-mounted on FR4 board using 1 in sq. pad size (Cu area 1.127 in sq. [1 oz] including traces).
- Surface-mounted on FR4 board using minimum recommended pad size (Cu area 0.412 in sq.).



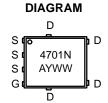
ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(on)} TYP	I _D MAX
30 V	6.0 mΩ @ 10 V	20 A
	8.0 mΩ @ 4.5 V	20 A







MARKING

4701N = Specific Device Code A = Assembly Location

Y = Year WW = Work Week

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4701NT1G	SO-8 FL (Pb-Free)	1500 Tape & Reel
NTMFS4701NT3G	SO-8 FL (Pb-Free)	5000 Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

THERMAL RESISTANCE RATINGS

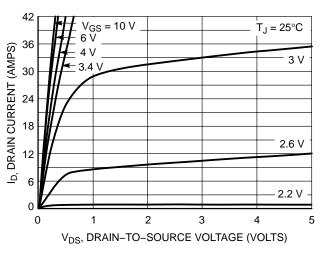
Rating	Symbol	Value www	w.D Uni 6hee	t4U.com
Junction-to-Case - Steady State	$R_{ heta JC}$	4.0	°C/W	
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	140		
Junction-to-Ambient - t ≤10 s (Note 1)	$R_{ heta JA}$	21		
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	55		

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise noted)

Characteristic	Symbol	Test Condition	on	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V, } I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				7.2		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V 04V 04V	$T_J = 25^{\circ}C$			1.0	μА
		$V_{GS} = 0 \text{ V}, V_{DS} = 24 \text{ V}$ $T_{J} = 125^{\circ}\text{C}$			50	1	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$				±100	nA
ON CHARACTERISTICS (Note 3)	•						
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 2$.50 μΑ	1.0		3.0	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 17 A			8.0	11	mΩ
	, ,	V _{GS} = 10 V, I _D =	20 A		6.0	8.0	1
Forward Transconductance	g _{FS}	V _{DS} = 15 V, I _D = 20 A			70		S
CHARGES, CAPACITANCES AND GATE R	ESISTANCE						·•
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1.0 MHz, V _{DS} = 24 V			1280		pF
Output Capacitance	C _{OSS}				500		
Reverse Transfer Capacitance	C _{RSS}				120		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V, I _D = 20 A			11	15	nC
Threshold Gate Charge	Q _{G(TH)}				1.1		
Gate-to-Source Charge	Q_{GS}				2.0		
Gate-to-Drain Charge	Q_{GD}				6.0		
Gate Resistance	R_{G}				1.4		Ω
SWITCHING CHARACTERISTICS, $V_{GS} = 4$.	5 V (Note 4)						
Turn-On Delay Time	t _{d(ON)}				9.0		ns
Rise Time	t _r	V _{GS} = 10 V, V _{DD} =	= 15 V,		4.0		7
Turn-Off Delay Time	t _{d(OFF)}	$V_{GS} = 10 \text{ V}, V_{DD} = I_D = 1.0 \text{ A}, R_G = 0$	6.0 Ω΄		29		1
Fall Time	t _f	1			19		1
DRAIN-SOURCE DIODE CHARACTERISTI	cs						
Forward Diode Voltage	V_{SD}	V 0V 1 00 1	T _J = 25°C		0.75	1.0	V
		$V_{GS} = 0 \text{ V}, I_S = 6.0 \text{ A}$	T _J = 125°C		0.55		1
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 6.0 \text{ A}$			34		ns
Charge Time	t _a				16		1
Discharge Time	t _b				18		1
Reverse Recovery Charge	Q_{RR}				27		nC

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

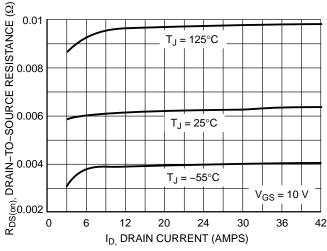


 $V_{DS} \ge 10 \text{ V}$ 36 DRAIN CURRENT (AMPS) 30 24 18 $T_J = 25^{\circ}C$ 12 <u>ٔ</u> 6 $T_{\rm J} = 125^{\circ}$ -55°C 0 3 0 V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

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Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



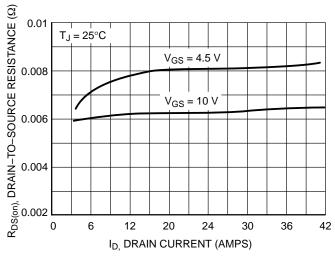
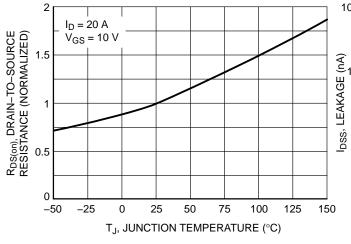


Figure 3. On–Resistance vs. Drain Current and Temperature

Figure 4. On–Resistance vs. Drain Current and Gate Voltage



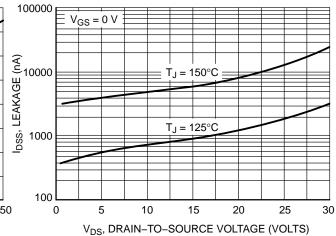
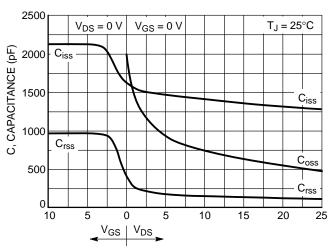


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation

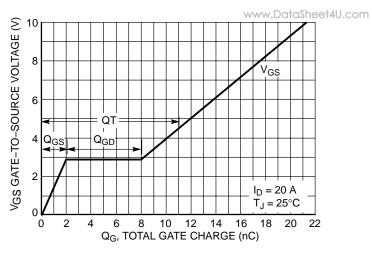


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

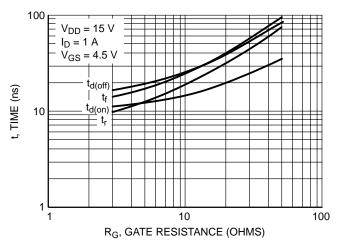


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

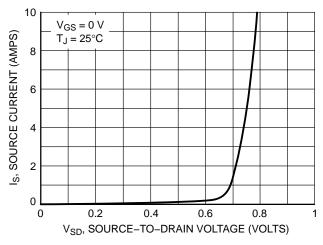


Figure 10. Diode Forward Voltage vs. Current

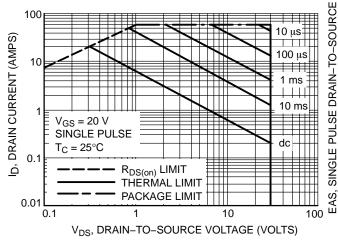


Figure 11. Maximum Rated Forward Biased Safe Operating Area

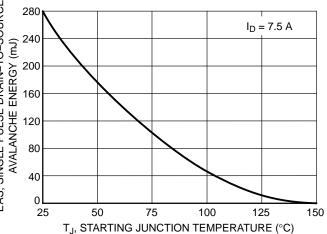
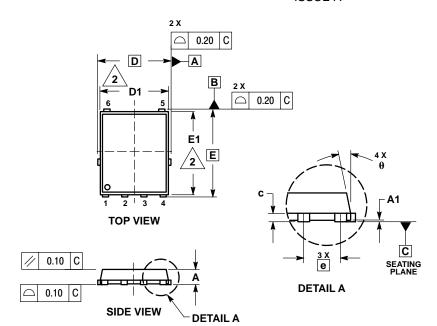


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

PACKAGE DIMENSIONS

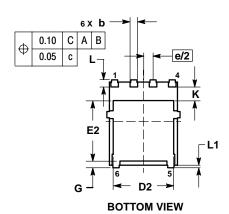
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SO-8 FLAT LEAD CASE 488AA-01 **ISSUE A**



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 2. CONTROLLING DIMENSION: MILLIMETER.
 3. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS					
DIM	MIN	NOM	MAX			
Α	0.90	0.99	1.20			
A1	0.00		0.05			
b	0.33	0.41	0.51			
С	0.23	0.28	0.33			
D		5.15 BSC				
D1	4.50	4.90	5.10			
D2	3.50		4.22			
Е		6.15 BSC				
E1	5.50	5.80	6.10			
E2	3.45		4.30			
е	1.27 BSC					
G	0.51	0.61	0.71			
K	0.51					
L	0.51	0.61	0.71			
L1	0.05	0.17	0.20			
θ	0 °		12 °			



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